



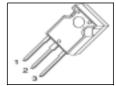
#### **Cool MOS™ Power Transistor**

#### **Feature**

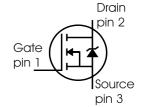
- New revolutionary high voltage technology
- Ultra low gate charge
- Periodic avalanche rated
- Extreme dv/dt rated
- Ultra low effective capacitances
- Improved transconductance
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC<sup>0)</sup> for target applications

V <sub>DS</sub> @ T <sub>imax</sub>	560	٧
R <sub>DS(on)</sub>	0.19	Ω
I <sub>D</sub>	21	Α

PG-TO247



Туре	Package	Ordering Code	Marking
SPW21N50C3	PG-TO247	Q67040-S4586	21N50C3



#### **Maximum Ratings**

Parameter	Symbol	Value	Unit
Continuous drain current	$I_{D}$		Α
$T_{\rm C}$ = 25 °C		21	
$T_{\rm C}$ = 100 °C		13.1	
Pulsed drain current, $t_p$ limited by $T_{jmax}$	I <sub>D puls</sub>	63	
Avalanche energy, single pulse	E <sub>AS</sub>	690	mJ
$I_{\rm D}$ = 10 A, $V_{\rm DD}$ = 50 V			
Avalanche energy, repetitive $t_{AR}$ limited by $T_{jmax}$ <sup>1</sup>	E <sub>AR</sub>	1	
$I_{\rm D}$ = 21 A, $V_{\rm DD}$ = 50 V			
Avalanche current, repetitive $t_{AR}$ limited by $T_{jmax}$	I <sub>AR</sub>	21	Α
Reverse diode dv/dt 4)	dv/dt	15	V/ns
Gate source voltage	$V_{GS}$	±20	V
Gate source voltage AC (f >1Hz)	V <sub>GS</sub>	±30	
Power dissipation, $T_{\text{C}} = 25^{\circ}\text{C}$	P <sub>tot</sub>	208	W
Operating and storage temperature	T <sub>j</sub> , T <sub>stg</sub>	-55 +150	°C



**Maximum Ratings** 

Parameter	Symbol	Value	Unit
Drain Source voltage slope	dv/dt	50	V/ns
$V_{\rm DS}$ = 400 V, $I_{\rm D}$ = 21 A, $T_{\rm j}$ = 125 °C			

#### **Thermal Characteristics**

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Thermal resistance, junction - case	R <sub>thJC</sub>	-	-	0.6	K/W
Thermal resistance, junction - ambient, leaded	R <sub>thJA</sub>	-	-	62	
Soldering temperature, wavesoldering	$T_{sold}$	_	-	260	°C
1.6 mm (0.063 in.) from case for 10s					

# **Electrical Characteristics,** at *T*j=25°C unless otherwise specified

Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =0.25mA	500	-	-	V
Drain-Source avalanche	V <sub>(BR)DS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =21A	-	600	-	
breakdown voltage						
Gate threshold voltage	V <sub>GS(th)</sub>	/ <sub>D</sub> =1000μA, V <sub>GS</sub> =V <sub>DS</sub>	2.1	3	3.9	
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> =500V, V <sub>GS</sub> =0V,				μΑ
		<i>T</i> <sub>j</sub> =25°C,	-	0.1	1	
		<i>T</i> <sub>j</sub> =150°C	-	-	100	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V	-	-	100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =13.1A,				Ω
	, ,	<i>T</i> <sub>j</sub> =25°C	-	0.16	0.19	
		<i>T</i> <sub>j</sub> =150°C	-	0.54	-	
Gate input resistance	R <sub>G</sub>	f=1MHz, open Drain	-	0.53	-	



**Electrical Characteristics**, at  $T_i$  = 25 °C, unless otherwise specified

Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Transconductance	<i>g</i> fs	$V_{DS} \ge 2*I_D*R_{DS(on)max}$ , $I_D = 13.1A$	-	18	-	S
Input capacitance	C <sub>iss</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =25V,	-	2400	-	pF
Output capacitance	$C_{oss}$	f=1MHz	-	1200	-	
Reverse transfer capacitance	C <sub>rss</sub>		-	30	-	
Effective output capacitance,2)	C <sub>o(er)</sub>	V <sub>GS</sub> =0V,	-	87	-	pF
energy related		V <sub>DS</sub> =0V to 400V				
Effective output capacitance,3)	C <sub>o(tr)</sub>		-	tbd	-	
time related						
Turn-on delay time	t <sub>d(on)</sub>	V <sub>DD</sub> =380V, V <sub>GS</sub> =0/10V,	-	10	-	ns
Rise time	$t_{r}$	$I_{\rm D}$ =21A, $R_{\rm G}$ =3.6Ω	-	5	-	
Turn-off delay time	t <sub>d(off)</sub>		-	67	-	
Fall time	<i>t</i> <sub>f</sub>		-	4.5	-	

## **Gate Charge Characteristics**

		,				_
Gate to source charge	$Q_{gs}$	V <sub>DD</sub> =380V, I <sub>D</sub> =21A	-	10	-	nC
Gate to drain charge	Q <sub>gd</sub>		-	50	-	
Gate charge total	Qg	V <sub>DD</sub> =380V, I <sub>D</sub> =21A,	-	95	-	
		V <sub>GS</sub> =0 to 10V				
Gate plateau voltage	V <sub>(plateau)</sub>	V <sub>DD</sub> =380V, I <sub>D</sub> =21A	-	5	-	V

<sup>&</sup>lt;sup>0</sup>J-STD20 and JESD22

<sup>&</sup>lt;sup>1</sup>Repetitve avalanche causes additional power losses that can be calculated as  $P_{\text{AV}} = E_{\text{AR}} * f$ .

 $<sup>^2</sup>C_{\mathrm{o(er)}}$  is a fixed capacitance that gives the same stored energy as  $C_{\mathrm{oss}}$  while  $V_{\mathrm{DS}}$  is rising from 0 to 80%  $V_{\mathrm{DSS}}$ .

 $<sup>^3</sup>C_{
m o(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{
m oss}$  while  $V_{
m DS}$  is rising from 0 to 80%  $V_{
m DSS}$ .

 $<sup>^4</sup>$ I<sub>SD</sub><=I<sub>D</sub>, di/dt<=200A/us, V<sub>DClink</sub>=400V, V<sub>peak</sub><V<sub>BR, DSS</sub>, T<sub>j</sub><T<sub>j,max</sub>. Identical low-side and high-side switch.

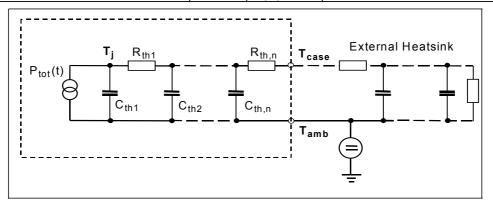


**Electrical Characteristics**, at  $T_j$  = 25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Conditions Values			Unit
			min.	typ.	max.	
Inverse diode continuous	IS	<i>T</i> <sub>C</sub> =25°C	-	-	21	Α
forward current						
Inverse diode direct current,	/ <sub>SM</sub>		-	-	63	
pulsed						
Inverse diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0V, I <sub>F</sub> =I <sub>S</sub>	-	1	1.2	V
Reverse recovery time	t <sub>rr</sub>	V <sub>R</sub> =380V, I <sub>F</sub> =I <sub>S</sub> ,	-	450	-	ns
Reverse recovery charge	Q <sub>rr</sub>	d <i>i<sub>F</sub></i> /d <i>t</i> =100A/μs	-	9	-	μC
Peak reverse recovery current	/ <sub>rrm</sub>		-	60	-	Α
Peak rate of fall of reverse	di <sub>rr</sub> /dt		-	1200	-	A/µs
recovery current						

**Typical Transient Thermal Characteristics** 

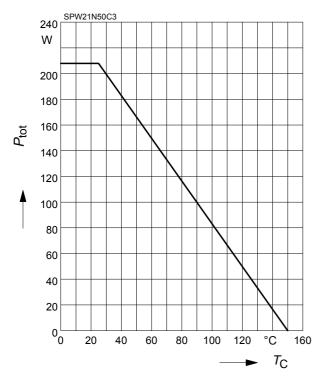
Symbol	Value	Unit	Symbol	Value	Unit
	typ.			typ.	
Thermal r	esistance		Thermal of	capacitance	
R <sub>th1</sub>	0.00769	K/W	C <sub>th1</sub>	0.0003763	Ws/K
R <sub>th2</sub>	0.015		C <sub>th2</sub>	0.001411	
R <sub>th3</sub>	0.029		C <sub>th3</sub>	0.001931	
R <sub>th4</sub>	0.114		C <sub>th4</sub>	0.005297	
R <sub>th5</sub>	0.136		C <sub>th5</sub>	0.012	
R <sub>th6</sub>	0.059		C <sub>th6</sub>	0.091	





#### 1 Power dissipation

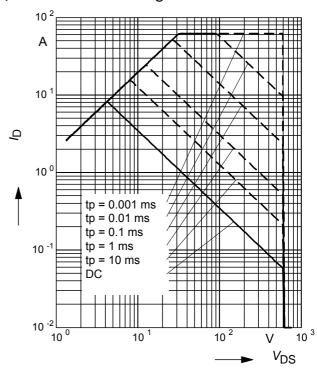
$$P_{\text{tot}} = f(T_{\text{C}})$$



#### 2 Safe operating area

$$I_{\mathsf{D}} = f(V_{\mathsf{DS}})$$

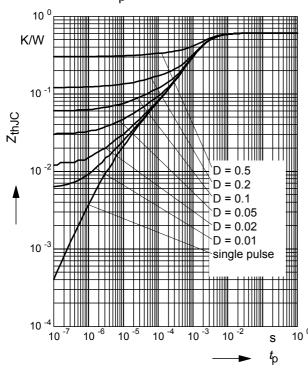
parameter : D = 0 ,  $T_C = 25$ °C



### 3 Transient thermal impedance

$$Z_{\text{thJC}} = f(t_{\text{p}})$$

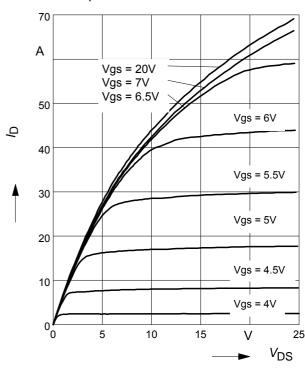
parameter:  $D = t_p/T$ 



## 4 Typ. output characteristic

 $I_{D} = f(V_{DS}); T_{j}=25^{\circ}C$ 

parameter:  $t_p$  = 10  $\mu$ s,  $V_{GS}$ 



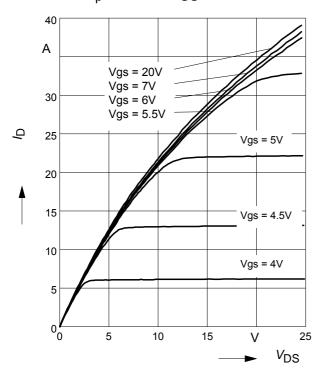
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## 5 Typ. output characteristic

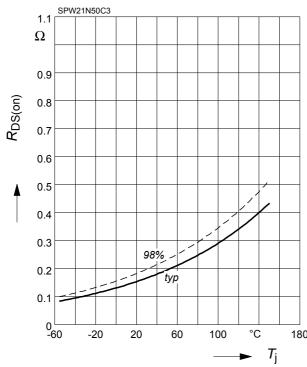
 $I_{D} = f(V_{DS}); T_{j}=150$ °C parameter:  $t_{p} = 10 \mu s, V_{GS}$ 



### 7 Drain-source on-state resistance

 $R_{\mathrm{DS(on)}} = f(T_{\mathrm{j}})$ 

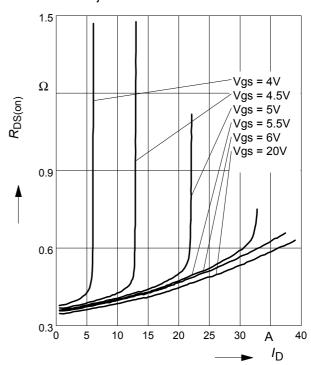
parameter :  $I_D$  = 13.1 A,  $V_{GS}$  = 10 V



#### 6 Typ. drain-source on resistance

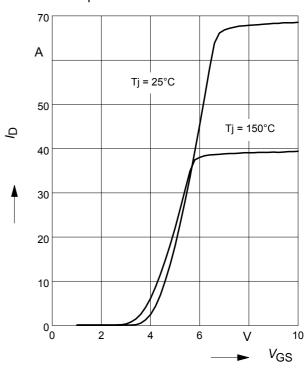
 $R_{\mathrm{DS(on)}} = f(I_{\mathrm{D}})$ 

parameter:  $T_i$ =150°C,  $V_{GS}$ 



#### 8 Typ. transfer characteristics

 $I_{\rm D}$ = f (  $V_{\rm GS}$  );  $V_{\rm DS}$  $\geq$  2 x  $I_{\rm D}$  x  $R_{\rm DS(on)max}$  parameter:  $t_{\rm p}$  = 10  $\mu$ s



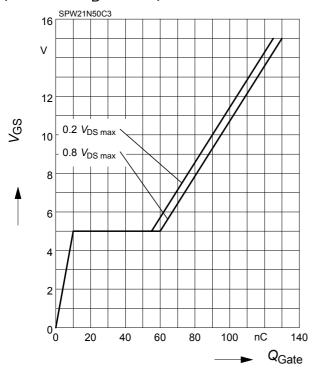
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#### 9 Typ. gate charge

 $V_{GS} = f (Q_{Gate})$ 

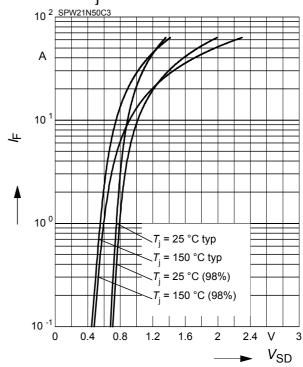
parameter:  $I_D$  = 21 A pulsed



#### 10 Forward characteristics of body diode

 $I_{\mathsf{F}} = f(\mathsf{V}_{\mathsf{SD}})$ 

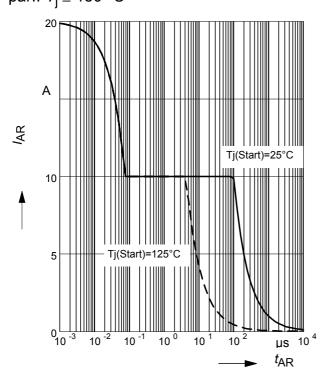
parameter:  $T_i$ ,  $t_p = 10 \mu s$ 



#### 11 Avalanche SOA

 $I_{AR} = f(t_{AR})$ 

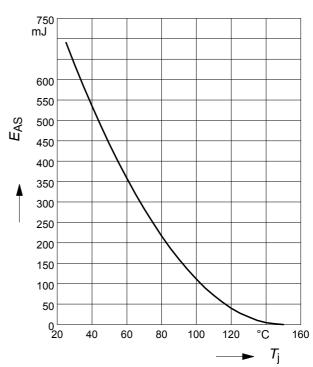
par.:  $T_j \le 150 \,^{\circ}\text{C}$ 



#### 12 Avalanche energy

 $E_{AS} = f(T_i)$ 

par.:  $I_D = 10 \text{ A}, V_{DD} = 50 \text{ V}$ 

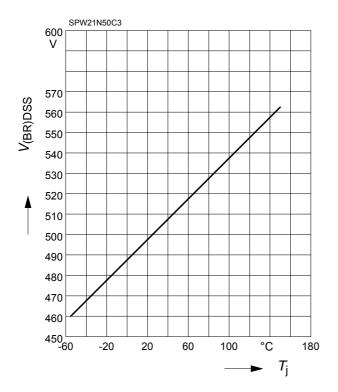


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#### 13 Drain-source breakdown voltage

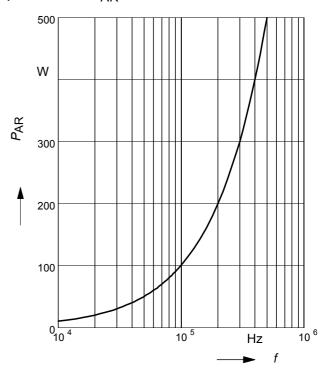
$$V_{(BR)DSS} = f(T_j)$$



#### 14 Avalanche power losses

$$P_{AR} = f(f)$$

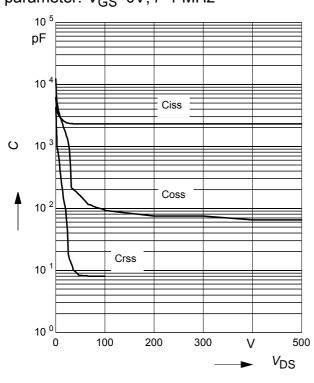
parameter: *E*<sub>AR</sub>=1mJ



## 15 Typ. capacitances

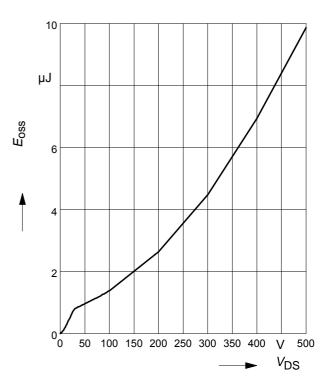
$$C = f(V_{DS})$$

parameter: V<sub>GS</sub>=0V, f=1 MHz



# 16 Typ. $C_{\rm OSS}$ stored energy

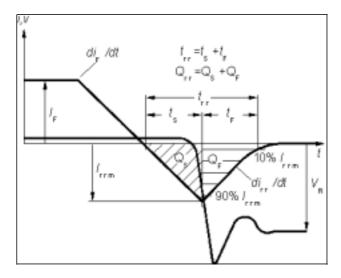
$$E_{\text{oss}} = f(V_{\text{DS}})$$



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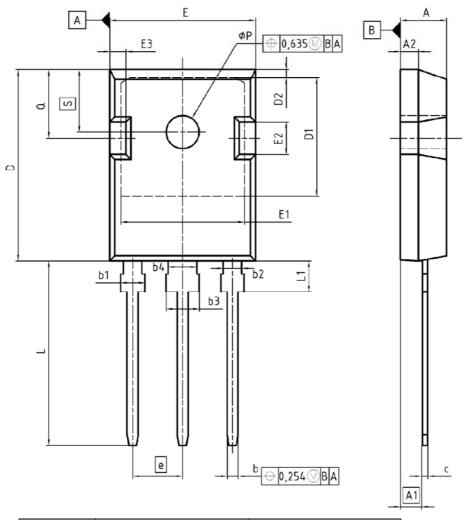


## Definition of diodes switching characteristics

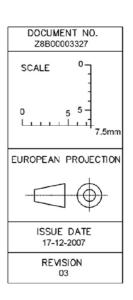




#### PG-TO-247-3-1



DIM	MILLIMETERS		INCH	HES
DIM	MIN	MAX	MIN	MAX
Α	4.90	5.16	0.193	0.203
A1	2.27	2.53	0.089	0.099
A2	1.85	2.11	0.073	0.083
ь	1.07	1.33	0.042	0.052
b1	1.90	2.41	0.075	0.095
b2	1.90	2.16	0.075	0.085
b3	2.87	3.38	0.113	0.133
b4	2.87	3.13	0.113	0.123
С	0.55	0.68	0.022	0.027
D	20.82	21.10	0.820	0.831
D1	16.25	17.65	0.640	0.695
D2	1.05	1.35	0.041	0.053
E	15.70	16.03	0.618	0.631
E1	13.10	14.15	0.516	0.557
E2	3.68	5.10	0.145	0.201
E3	1.68	2.60	0.066	0.102
е	5.	44	0.2	214
N		3	;	3
L	19.80	20.31	0.780	0.799
L1	4.17	4.47	0.164	0.176
øР	3.50	3.70	0.138	0.146
Q	5.49	6.00	0.216	0.236
S	6.04	6.30	0.238	0.248





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New package outlines TO-247

# 1 New package outlines TO-247

Assembly capacity extension for CoolMOSTM technology products assembled in lead-free package PG-TO247-3 at subcontractor ASE (Weihai) Inc., China (Changes are marked in blue.)

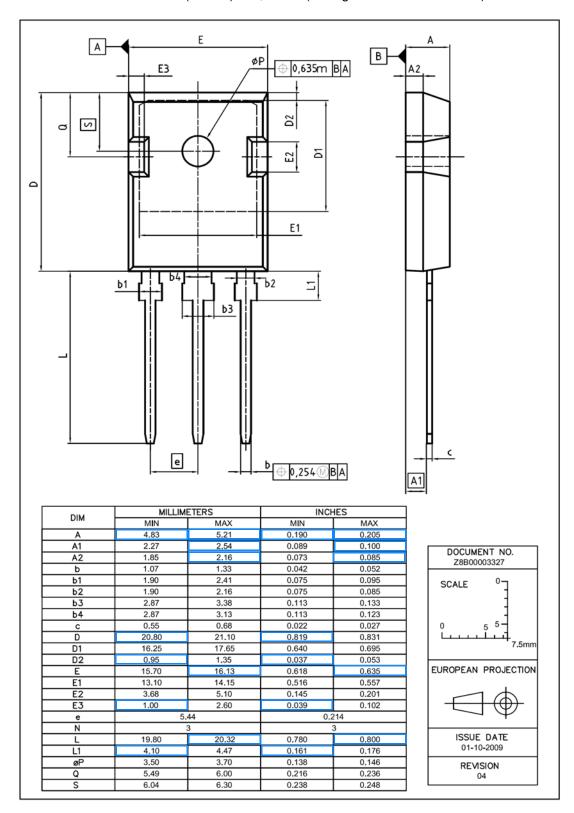


Figure 1 Outlines TO-247, dimensions in mm/inches

Final Data Sheet Erratum Rev. 2.0, 2010-02-01

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